## **Power MOSFET**

### 20 V/–20 V, 4.6 A/–4.1 A, μCool<sup>™</sup> Complementary, 2x2 mm, WDFN Package Features

- Complementary N-Channel and P-Channel MOSFET
- WDFN Package with Exposed Drain Pad for Excellent Thermal Conduction
- Footprint Same as SC-88 Package
- Leading Edge Trench Technology for Low On Resistance
- 1.8 V Gate Threshold Voltage
- Low Profile (< 0.8 mm) for Easy Fit in Thin Environments
- This is a Pb–Free Device

#### Applications

- Synchronous DC-DC Conversion Circuits
- Load/Power Management of Portable Devices like PDA's, Cellular Phones and Hard Drives
- Color Display and Camera Flash Regulators

#### **MAXIMUM RATINGS** (T<sub>J</sub> = $25^{\circ}C$ unless otherwise noted)

Paran	neter		Symbol	Value	Unit
Drain-to-Source Voltag	ge	N-Ch	V <sub>DSS</sub>	20	V
				-20	
Gate-to-Source Voltag	le	N-Ch	V <sub>GS</sub>	±8.0	V
		P-Ch			
N-Channel	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	3.8	Α
Continuous Drain Current (Note 1)	State	T <sub>A</sub> = 85°C		2.8	
, , , , , , , , , , , , , , , , , , ,	t≤5 s	T <sub>A</sub> = 25°C		4.6	
P-Channel	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	-3.3	A
Continuous Drain Current (Note 1)	State	T <sub>A</sub> = 85°C		-2.4	
, , , , , , , , , , , , , , , , , , ,	t≤5s	T <sub>A</sub> = 25°C		-4.1	
Power Dissipation (Note 1)	Steady State	T₄ = 25°C	PD	1.5	W
(	t ≤ 5 s	$I_{A} = 25 \text{ C}$		2.3	
N-Channel	Steady	T <sub>A</sub> = 25°C	ID	2.6	А
Continuous Drain Current (Note 2)	State	T <sub>A</sub> = 85°C		1.9	
P-Channel	Steady	T <sub>A</sub> = 25°C	Ι <sub>D</sub>	-2.3	А
Continuous Drain Current (Note 2)	State	T <sub>A</sub> = 85°C		-1.6	
Power Dissipation (Note 2)	Steady State	$T_A = 25^{\circ}C$	PD	0.71	W
Pulsed Drain Current	N-Ch	t <sub>p</sub> = 10 μs	I <sub>DM</sub>	18	А
		-20			
Operating Junction and	T <sub>J</sub> , T <sub>STG</sub>	–55 to 150	°C		
Lead Temperature for S (1/8" from case for 10 s		urposes	ΤL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

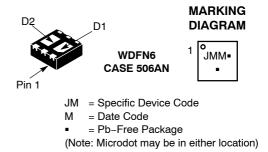
- 1. Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces).
- Surface Mounted on FR4 Board using the minimum recommended pad size of 30 mm<sup>2</sup>, 2 oz Cu.



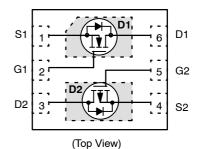
### **ON Semiconductor®**

#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
	65 mΩ @ 4.5 V	3.8 A
N–Channel 20 V	85 mΩ @ 2.5 V	2.0 A
	120 mΩ @ 1.8 V	1.7 A
D. Ohannal	100 mΩ @ –4.5 V	-4.1 A
P-Channel -20 V	135 mΩ @ −2.5 V	–2.0 A
	200 mΩ @ −1.8 V	–1.6 A



#### PIN CONNECTIONS



### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTLJD3119CTAG	WDFN6 (Pb-Free)	3000/Tape & Reel
NTLJD3119CTBG	WDFN6 (Pb-Free)	3000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
SINGLE OPERATION (SELF-HEATED)			
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	83	
Junction-to-Ambient - Steady State Min Pad (Note 4)	R <sub>0JA</sub>	177	°C/W
Junction-to-Ambient – t $\leq$ 5 s (Note 3)	$R_{ heta JA}$	54	
DUAL OPERATION (EQUALLY HEATED)			
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	58	
Junction-to-Ambient - Steady State Min Pad (Note 4)	R <sub>0JA</sub>	133	°C/W
Junction-to-Ambient – t $\leq$ 5 s (Note 3)	R <sub>θJA</sub>	40	

Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces).
Surface Mounted on FR4 Board using the minimum recommended pad size (30 mm<sup>2</sup>, 2 oz Cu).

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Symbol	N/P	Test Conditions		Min	Тур	Max	Unit		
OFF CHARACTERISTICS										
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	Ν	N 0.V	I <sub>D</sub> = 250 μA	20			V		
		Р	V <sub>GS</sub> = 0 V	I <sub>D</sub> = -250 μA	-20					
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub> /T <sub>J</sub>	Ν				10.4		mV/°C		
Temperature Coefficient		Р				9.95				
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	Ν	$V_{GS}$ = 0 V, $V_{DS}$ = 16 V	T 05 %C			1.0	μΑ		
		Р	$V_{GS}$ = 0 V, $V_{DS}$ = -16 V	T <sub>J</sub> = 25 °C			-1.0			
		Ν	$V_{GS}$ = 0 V, $V_{DS}$ = 16 V	т ог оо			10			
		Р	$V_{GS}$ = 0 V, $V_{DS}$ = -16 V	T <sub>J</sub> = 85 °C			-10			
Gate-to-Source Leakage Current	-Source Leakage Current $I_{GSS}$ N $V_{DS} = 0 V, V_{GS} = \pm 8.0 V$		±8.0 V			±100	nA			
		Р	$V_{DS} = 0 V, V_{GS} =$	±8.0 V			±100	1		

#### **ON CHARACTERISTICS** (Note 5)

Gate Threshold Voltage	V <sub>GS(TH)</sub>	Ν		I <sub>D</sub> = 250 μA	0.4	0.7	1.0	V
		Р	$V_{GS} = V_{DS}$	I <sub>D</sub> = -250 μA	-0.4	-0.7	-1.0	1
Gate Threshold Temperature	V <sub>GS(TH)</sub> /T <sub>J</sub>	Ν				-3.0		mV/°C
Coefficient		Р				2.44		1
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	Ν	$V_{GS}$ = 4.5 V , I <sub>D</sub> = 3.8 A			37	65	mΩ
		Р	$V_{GS}$ = -4.5 V , $I_D$ = -4.1 A			75	100	
		Ν	$V_{GS}$ = 2.5 V , I <sub>D</sub> =	= 2.0 A		46	85	
		Р	$V_{GS}$ = -2.5 V, I <sub>D</sub> =	–2.0 A		101	135	
		Ν	$V_{GS}$ = 1.8 V , $I_D$ = 1.7 A			65	120	
		Р	V <sub>GS</sub> = -1.8 V, I <sub>D</sub> =	–1.6 A		150	200	
Forward Transconductance	9fs	Ν	V <sub>DS</sub> = 10 V, I <sub>D</sub> =	1.7 A		4.2		S
		Р	$V_{DS}$ = -5.0 V , $I_D$ =	= -2.0 A		3.1		]

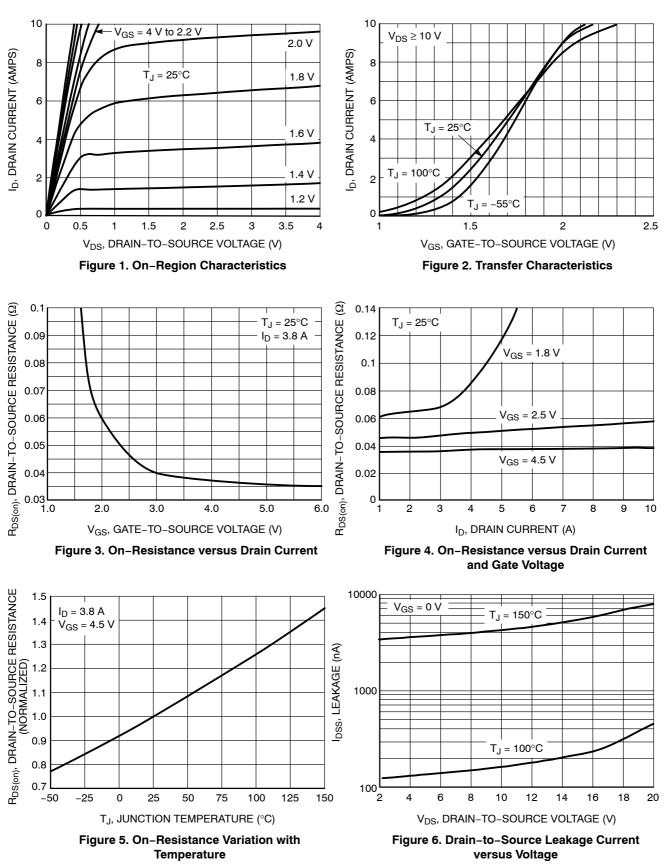
#### CHARGES, CAPACITANCES AND GATE RESISTANCE

Input Capacitance	C <sub>ISS</sub>	Ν		V <sub>DS</sub> = 10 V	271		pF
		Р		V <sub>DS</sub> = -10 V	531		
Output Capacitance	C <sub>OSS</sub>	Ν		V <sub>DS</sub> = 10 V	72		
		Р	f = 1.0 MHz, V <sub>GS</sub> = 0 V	V <sub>DS</sub> = -10 V	91		
Reverse Transfer Capacitance	C <sub>RSS</sub>	Ν		V <sub>DS</sub> = 10 V	43		
		Р		V <sub>DS</sub> = -10 V	56		
Total Gate Charge	Q <sub>G(TOT)</sub>	Ν	$V_{GS}$ = 4.5 V, $V_{DS}$ = 10 V, $I_{D}$ = 3.8 A		3.7		nC
		Р	$V_{GS}$ = –4.5 V, $V_{DS}$ = –10 V, $I_{D}$ = –2.0 A		5.5		
Threshold Gate Charge	Q <sub>G(TH)</sub>	Ν	$V_{GS} = 4.5 \text{ V}, V_{DS} = 10 \text{ V}, I_D = 3.8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V}, I_D = -2.0 \text{ A}$		0.3		
		Р			0.7		
Gate-to-Source Charge	Q <sub>GS</sub>	Ν	$V_{GS} = 4.5 \text{ V}, V_{DS} = 10^{\circ}$	V, I <sub>D</sub> = 3.8 A	0.6		
		Р	$V_{GS} = -4.5$ V, $V_{DS} = -10$	V, $I_{D} = -2.0 \text{ A}$	1.0		
Gate-to-Drain Charge	Q <sub>GD</sub>	Ν	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 10	V, I <sub>D</sub> = 3.8 A	1.0		
		Р	$V_{GS} = -4.5 \text{ V}, \text{ V}_{DS} = -10$	V, I <sub>D</sub> = -2.0 A	1.4		

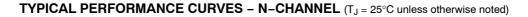
### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

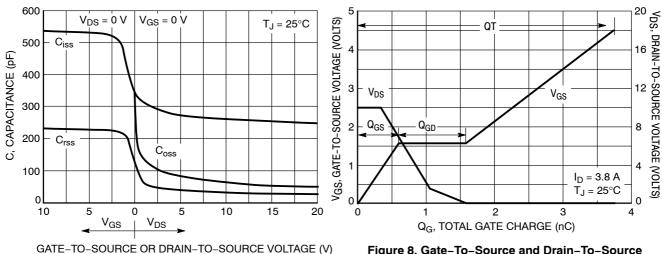
Parameter	Symbol	N/P	Test Conditions			Тур	Max	Unit
SWITCHING CHARACTERISTIC	<b>S</b> (Note 6)					8		
Turn-On Delay Time	t <sub>d(ON)</sub>					3.8		ns
Rise Time	t <sub>r</sub>	N	V <sub>GS</sub> = 4.5 V, V <sub>D</sub>	$V_{GS}$ = 4.5 V, $V_{DD}$ = 16 V, $I_{D}$ = 1.0 A, $R_{G}$ = 2.0 $\Omega$		4.7		
Turn-Off Delay Time	t <sub>d(OFF)</sub>		$I_{\rm D} = 1.0 \text{ A}, \text{ R}_{\rm G} =$			11.1		
Fall Time	t <sub>f</sub>					5.8		
Turn-On Delay Time	t <sub>d(ON)</sub>					5.2		
Rise Time	t <sub>r</sub>		VGS = -4.5 V. VDD	= –10 V.		13.2		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	Р	$I_{\rm D} = -2.0 \text{ A}, \text{ R}_{\rm G} =$	$V_{GS}$ = -4.5 V, $V_{DD}$ = -10 V, $I_{D}$ = -2.0 A, $R_{G}$ = 2.0 $\Omega$		13.7		
Fall Time	t <sub>f</sub>					19.1		
DRAIN-SOURCE DIODE CHAR	ACTERISTICS					1		
Forward Diode Voltage	V <sub>SD</sub>	Ν		I <sub>S</sub> = 1.0 A		0.69	1.0	V
	P V <sub>GS</sub> = 0 V, T <sub>J</sub> = 25 °C	I <sub>S</sub> = -1.0 A		-0.75	-1.0			
		Ν	N/ 0.1/ T 105.00	l <sub>S</sub> = 1.0 A		0.52		1
		Р	V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	I <sub>S</sub> = -1.0 A		-0.64		
Reverse Recovery Time	t <sub>RR</sub>	Ν		l <sub>S</sub> = 1.0 A		10.2		ns
		Р		I <sub>S</sub> = -1.0 A		16.2		
Charge Time	t <sub>a</sub>	Ν		l <sub>S</sub> = 1.0 A		6.0		
		Р	$V_{GS} = 0 V.$	I <sub>S</sub> = -1.0 A		10.6		
Discharge Time	t <sub>b</sub>	Ν		I <sub>S</sub> = 1.0 A		4.2		
		Р		I <sub>S</sub> = -1.0 A		5.6		
Reverse Recovery Charge	Q <sub>RR</sub>	Ν		I <sub>S</sub> = 1.0 A		3.0		nC
		Р		I <sub>S</sub> = -1.0 A		5.7		

5. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.



TYPICAL PERFORMANCE CURVES - N-CHANNEL (T<sub>J</sub> = 25°C unless otherwise noted)





E VOLTAGE (V) Figure 8. Gate-To-Source and Drain-To-Source Voltage versus Total Charge

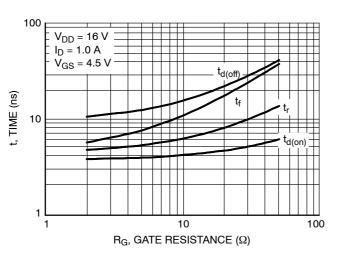


Figure 7. Capacitance Variation

Figure 9. Resistive Switching Time Variation versus Gate Resistance

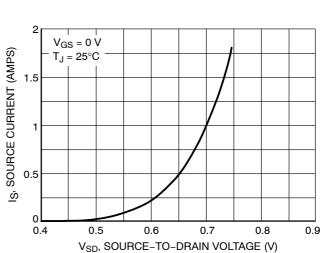
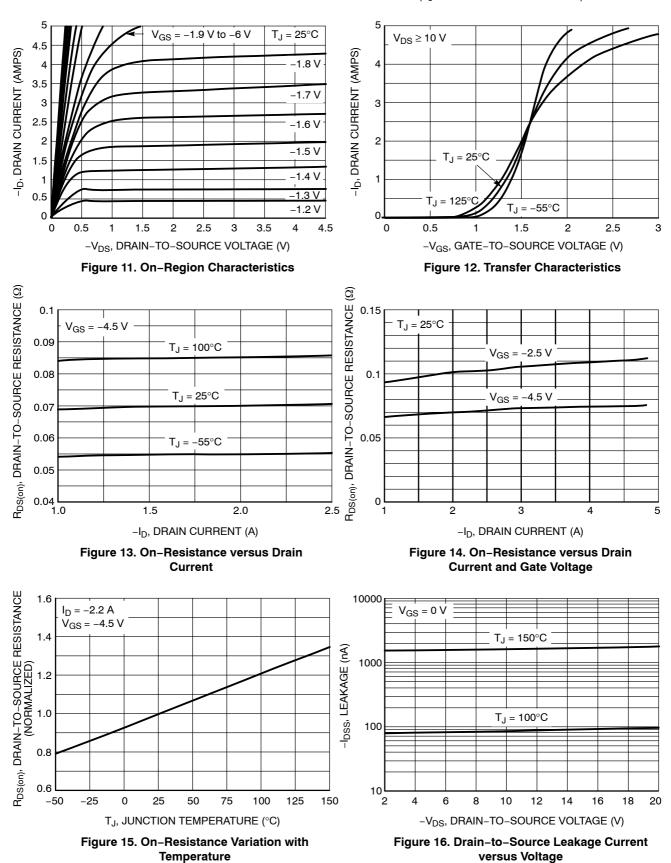
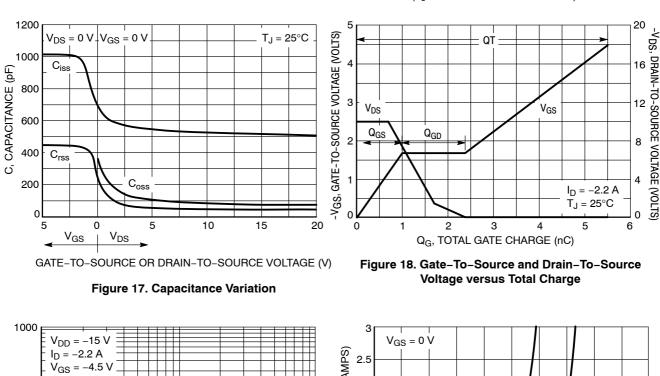


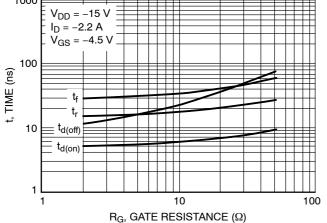
Figure 10. Diode Forward Voltage versus Current



TYPICAL PERFORMANCE CURVES - P-CHANNEL (T<sub>J</sub> = 25°C unless otherwise noted)



TYPICAL PERFORMANCE CURVES - P-CHANNEL (T<sub>J</sub> = 25°C unless otherwise noted)





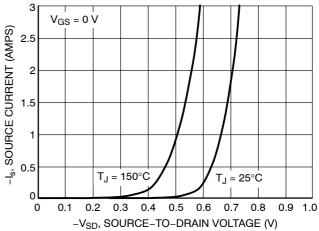


Figure 20. Diode Forward Voltage versus Current

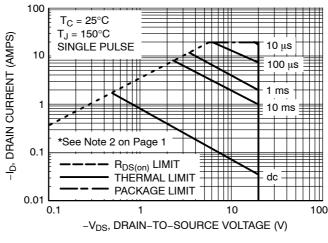
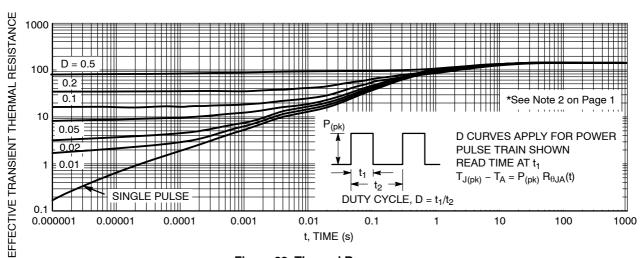


Figure 21. Maximum Rated Forward Biased Safe Operating Area

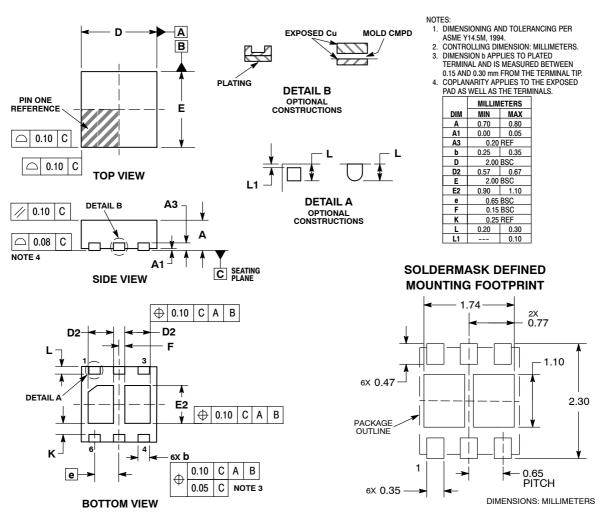


#### TYPICAL PERFORMANCE CURVES (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Figure 22. Thermal Response

#### PACKAGE DIMENSIONS

WDFN6, 2x2, 0.65P CASE 506AN-01 ISSUE D



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